

TOSHIBA Transistor Silicon NPN Epitaxial Planar Type

# 2SC5090

## VHF~UHF Band Low Noise Amplifier Applications

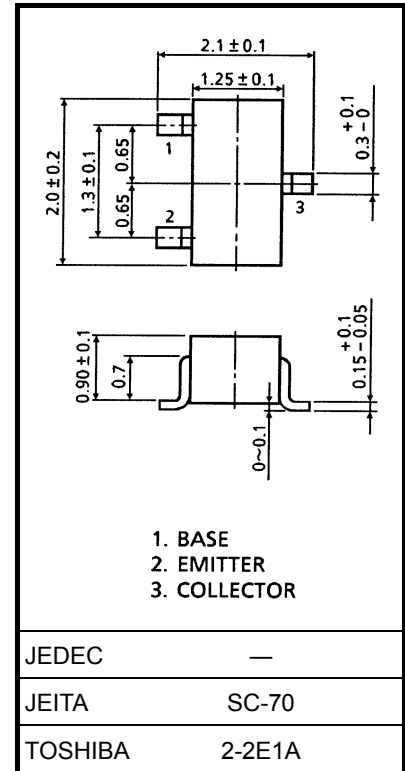
- Low noise figure, high gain.
- $NF = 1.1\text{dB}$ ,  $|S_{21e}|^2 = 13\text{dB}$  ( $f = 1\text{GHz}$ )

### Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	20	V
Collector-emitter voltage	$V_{CEO}$	10	V
Emitter-base voltage	$V_{EBO}$	1.5	V
Base current	$I_B$	20	mA
Collector current	$I_C$	40	mA
Collector power dissipation	$P_C$	100	mW
Junction temperature	$T_j$	125	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55~125	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Unit: mm



Weight: 0.006 g (typ.)

### Microwave Characteristics ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Transition frequency	$f_T$	$V_{CE} = 8\text{V}$ , $I_C = 20\text{mA}$	7	10	—	GHz
Insertion gain	$ S_{21e} ^2$ (1)	$V_{CE} = 8\text{V}$ , $I_C = 20\text{mA}$ , $f = 1\text{GHz}$	10	13	—	dB
	$ S_{21e} ^2$ (2)	$V_{CE} = 8\text{V}$ , $I_C = 20\text{mA}$ , $f = 2\text{GHz}$	—	7	—	
Noise figure	NF (1)	$V_{CE} = 8\text{V}$ , $I_C = 5\text{mA}$ , $f = 1\text{GHz}$	—	1.1	2.5	dB
	NF (2)	$V_{CE} = 8\text{V}$ , $I_C = 5\text{mA}$ , $f = 2\text{GHz}$	—	1.7	—	

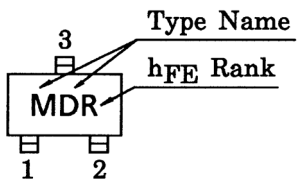
### Electrical Characteristics ( $T_a = 25^\circ\text{C}$ )

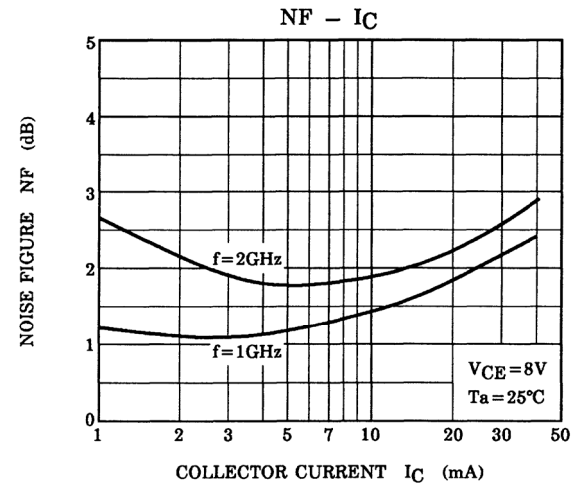
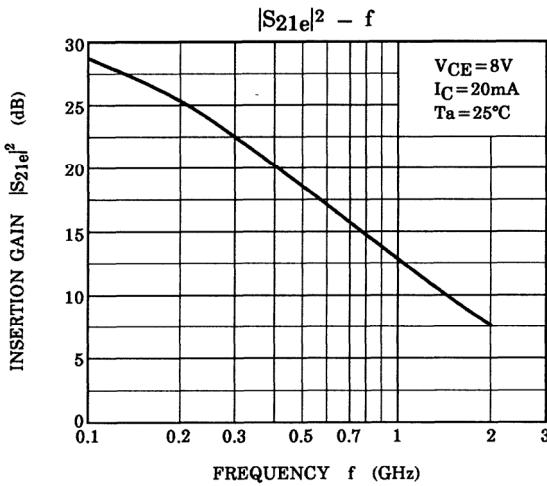
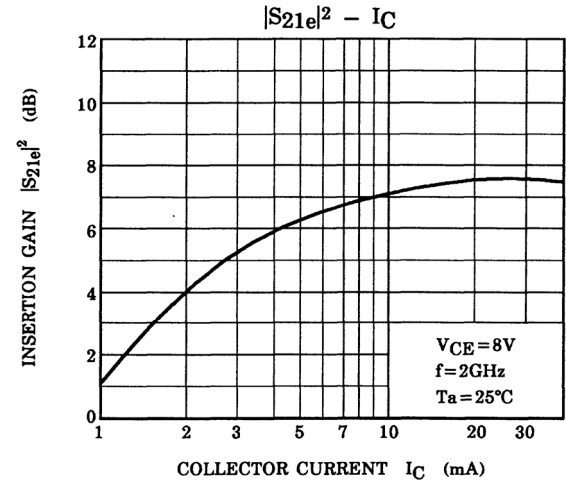
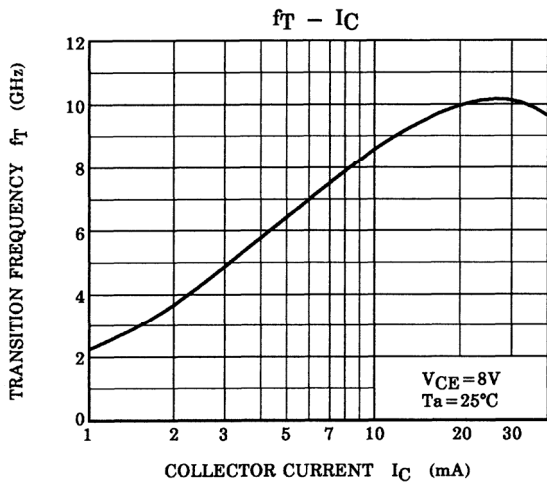
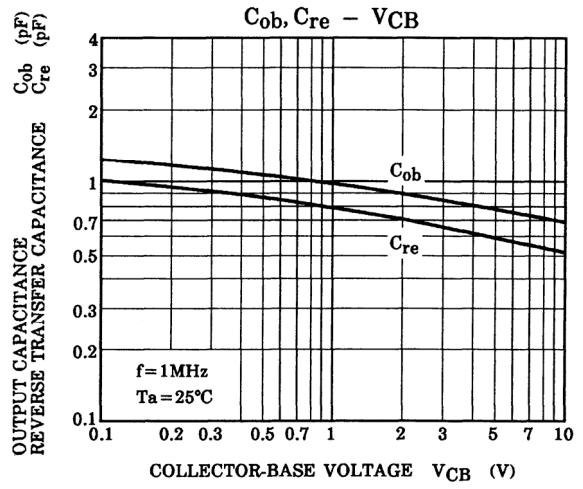
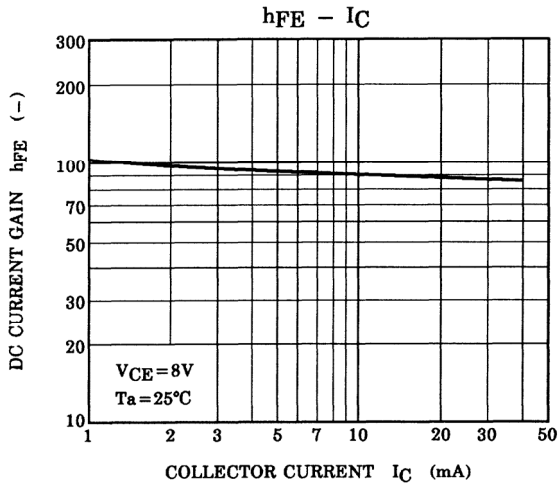
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current	$I_{CBO}$	$V_{CB} = 10\text{V}$ , $I_E = 0$	—	—	1	$\mu\text{A}$
Emitter cut-off current	$I_{EBO}$	$V_{EB} = 1\text{V}$ , $I_C = 0$	—	—	1	$\mu\text{A}$
DC current gain	$h_{FE}$ (Note 1)	$V_{CE} = 8\text{V}$ , $I_C = 20\text{mA}$	50	—	160	
Output capacitance	$C_{ob}$	$V_{CB} = 10\text{V}$ , $I_E = 0$ , $f = 1\text{MHz}$ (Note 2)	—	0.7	—	pF
Reverse transfer capacitance	$C_{re}$		—	0.5	0.95	pF

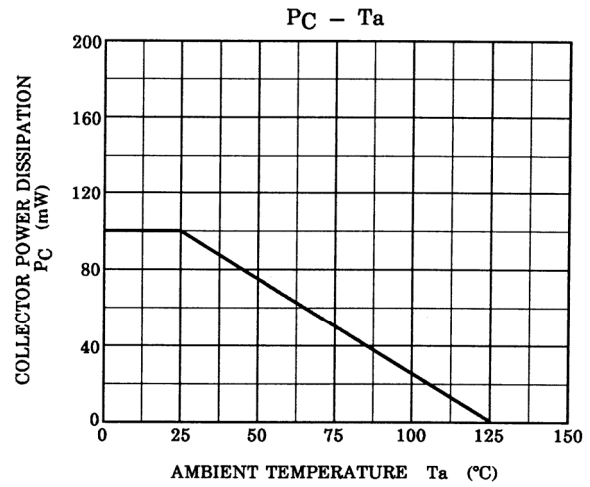
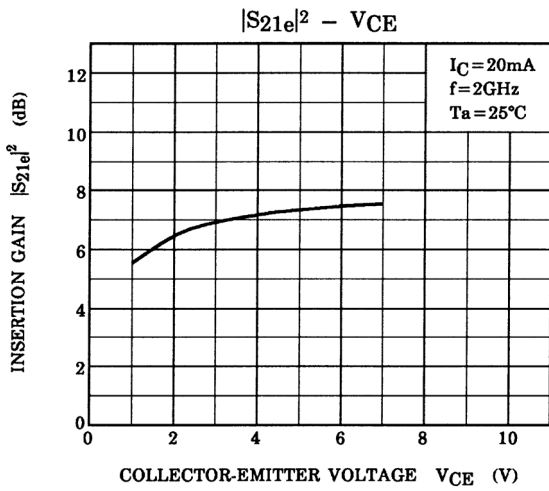
Note 1:  $h_{FE}$  classification R: 50~100, O: 80~160

Note 2:  $C_{re}$  is measured by 3 terminal method with capacitance bridge.

## Marking







**S-Parameter  $Z_O = 50 \Omega, T_a = 25^\circ C$**

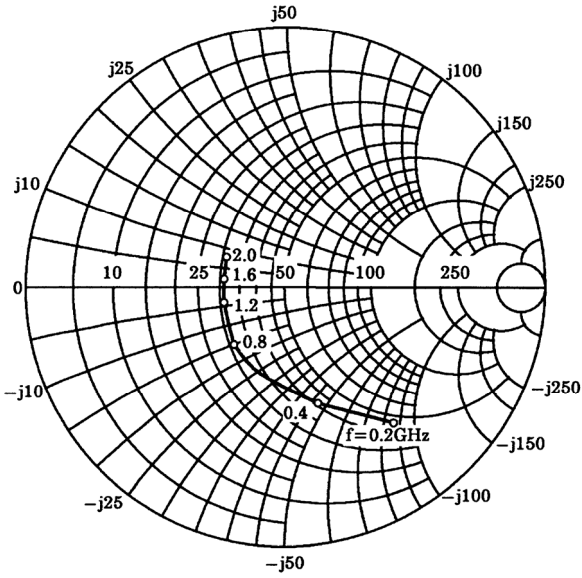
**$V_{CE} = 8 V, I_C = 5 mA$**

Frequency (MHz)	S11		S21		S12		S22	
	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.683	-50.1	10.186	138.3	0.049	62.0	0.773	-30.0
400	0.462	-86.9	7.472	114.6	0.071	54.3	0.556	-39.6
600	0.343	-113.1	5.618	100.9	0.086	53.8	0.448	-41.7
800	0.282	-133.6	4.407	91.7	0.101	55.3	0.392	-41.6
1000	0.249	-151.0	3.663	84.7	0.115	57.2	0.360	-41.7
1200	0.236	-166.6	3.128	78.7	0.131	58.9	0.339	-41.7
1400	0.233	179.7	2.759	73.1	0.150	60.1	0.330	-42.8
1600	0.234	168.3	2.457	68.2	0.168	60.0	0.319	-45.0
1800	0.238	158.6	2.224	63.4	0.185	60.0	0.311	-47.9
2000	0.251	149.6	2.038	59.4	0.203	60.4	0.302	-50.2

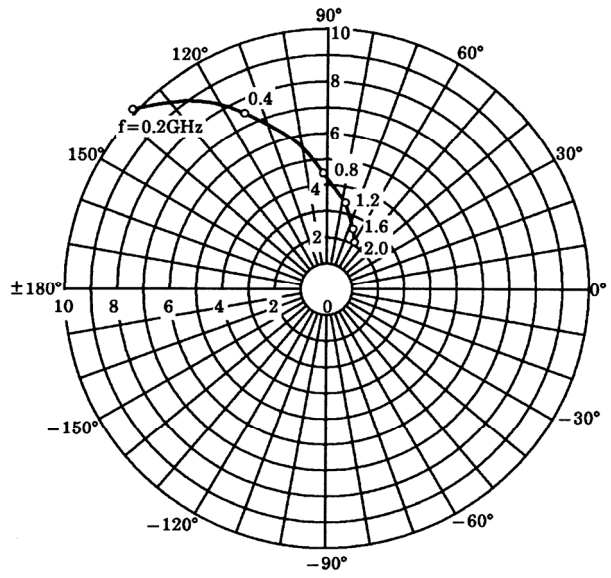
**$V_{CE} = 8 V, I_C = 20 mA$**

Frequency (MHz)	S11		S21		S12		S22	
	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.319	-91.9	18.338	116.7	0.033	65.3	0.494	-43.5
400	0.213	-134.2	10.303	99.2	0.054	68.9	0.312	-42.4
600	0.185	-160.0	7.111	90.3	0.076	70.8	0.258	-37.6
800	0.176	-178.2	5.415	84.3	0.098	71.2	0.236	-34.3
1000	0.174	167.8	4.400	79.2	0.120	71.1	0.228	-32.0
1200	0.178	156.8	3.712	74.8	0.143	70.3	0.226	-31.5
1400	0.186	147.5	3.236	70.3	0.168	68.7	0.226	-32.8
1600	0.194	139.7	2.874	66.3	0.190	66.6	0.223	-35.9
1800	0.199	133.7	2.583	62.6	0.211	64.9	0.216	-39.0
2000	0.215	127.8	2.369	58.8	0.232	63.5	0.211	-41.9

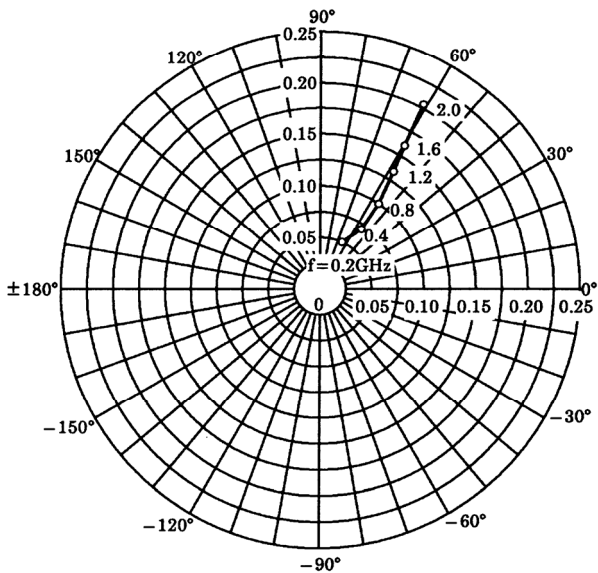
**S<sub>11e</sub>**  
**V<sub>CE</sub> = 8V**  
**I<sub>C</sub> = 5mA**  
**T<sub>a</sub> = 25°C**  
 (UNIT : Ω)



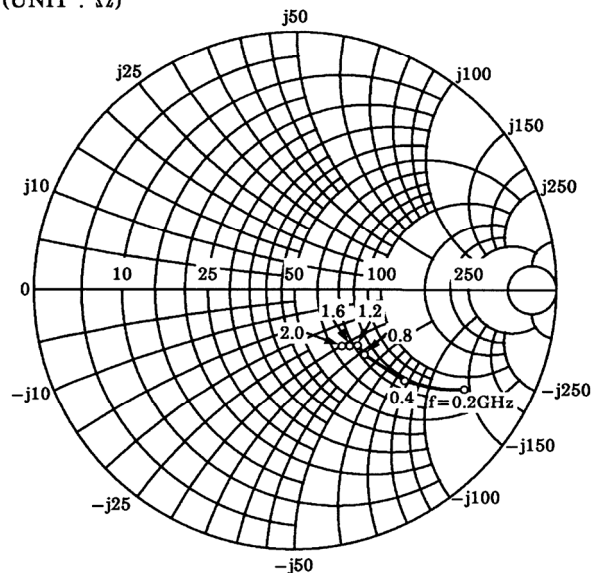
**S<sub>21e</sub>**  
**V<sub>CE</sub> = 8V**  
**I<sub>C</sub> = 5mA**  
**T<sub>a</sub> = 25°C**



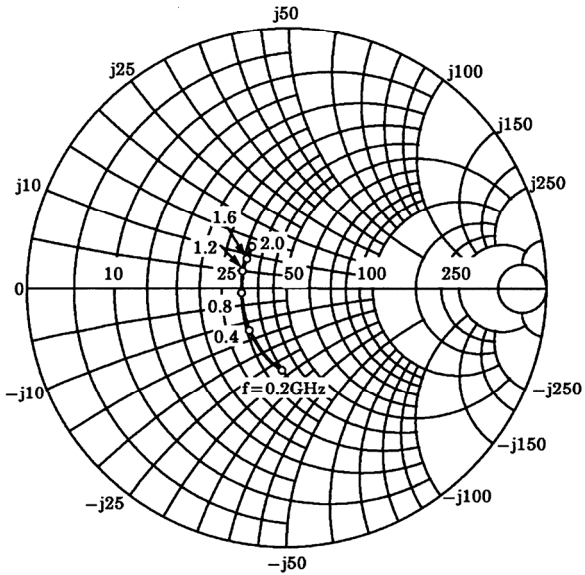
**S<sub>12e</sub>**  
**V<sub>CE</sub> = 8V**  
**I<sub>C</sub> = 5mA**  
**T<sub>a</sub> = 25°C**



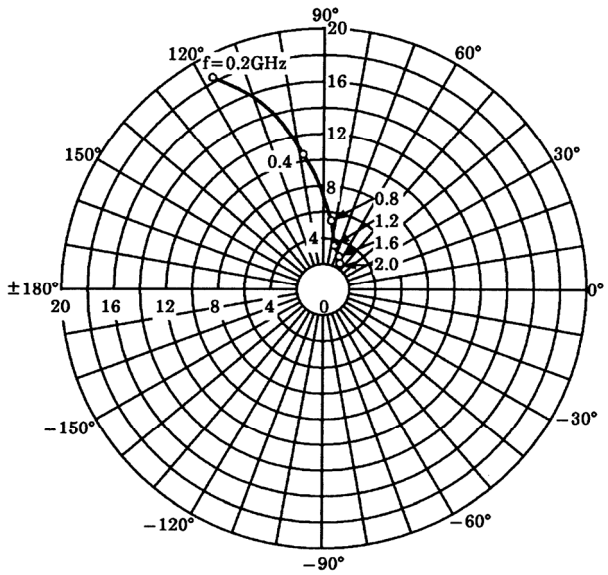
**S<sub>22e</sub>**  
**V<sub>CE</sub> = 8V**  
**I<sub>C</sub> = 5mA**  
**T<sub>a</sub> = 25°C**  
 (UNIT : Ω)



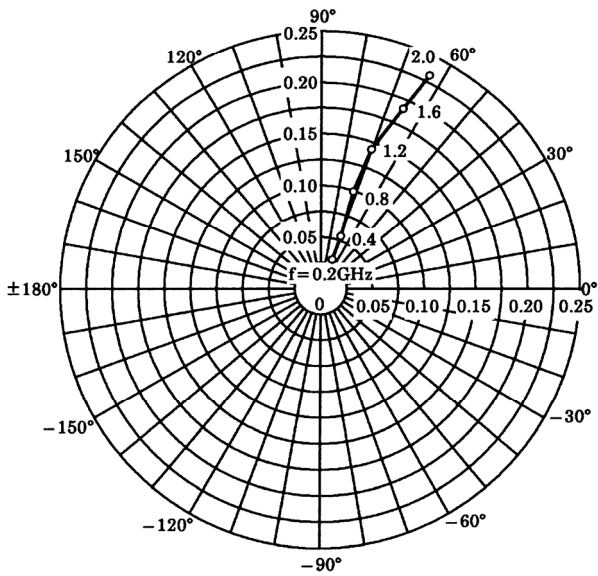
S11e  
 VCE=8V  
 IC=20mA  
 Ta=25°C  
 (UNIT : Ω)



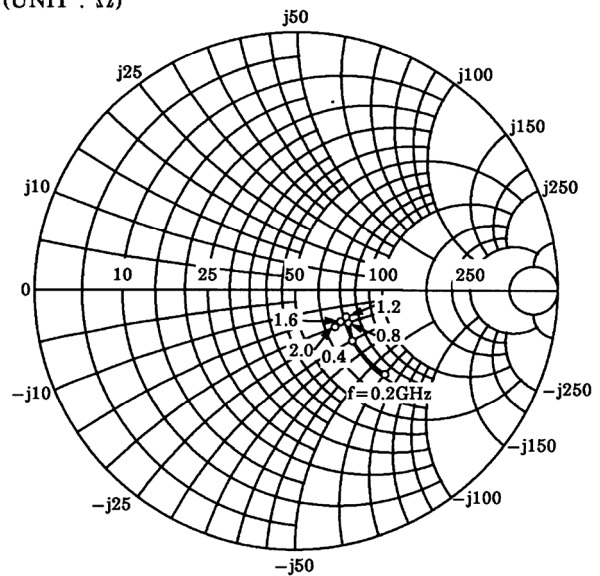
S21e  
 VCE=8V  
 IC=20mA  
 Ta=25°C



S12e  
 VCE=8V  
 IC=20mA  
 Ta=25°C



S22e  
 VCE=8V  
 IC=20mA  
 Ta=25°C  
 (UNIT : Ω)



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